

Notice of References Cited	Application/Control No. 09/837,216	Applicant(s)/Patent Under Reexamination KITAMURA, YOSHIMASA	
	Examiner Hai V. Nguyen	Art Unit 2142	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2006/0077278	04-2006	Parulski et al.	348/333.01
*	B	US-2005/0064887	03-2005	Bengtsson et al.	455/466
*	C	US-2002/0032785	03-2002	Britt, Joe Freeman JR.	709/229
*	D	US-2002/0032027	03-2002	Kirani et al.	455/426
*	E	US-2001/0036231	11-2001	Easwar et al.	375/240.19
*	F	US-2001/0035979	11-2001	Pornbacher, Fritz	358/400
*	G	US-7,025,209	04-2006	Hawkins, Jeffrey C.	209/217
*	H	US-6,499,016	12-2002	Anderson, Eric C.	704/275
*	I	US-6,317,609	11-2001	Alperovich et al.	455/556.1
*	J	US-6,690,403	02-2004	Tuli, Raja	715/854
*	K	US-6,507,865	01-2003	Hanson et al.	705/36R
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.